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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known					
Application Number	09/917,842				
Filing Date	July 27, 2001				
First Named Inventor	Chin, et al.				
Art Unit	2125				
Examiner Name	Not yet assigned				
Attorney Docket Number	5017/ISM/CORE/ MCVD/SB				

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Examinar	Cite	Occument Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relays:		
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Initials*	No.1			Applicant of Cited Document		T ⁶			

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Sheet of 2

Apatherion Number	09/917,842
Filing Date	July 27, 2001
First Named Inventor	Chin, et al.
Group Art Unit	2125
Examiner Name	Kosowski
Attorney Docket Number	5017/ISM/CORE/MCVD
Submission Date	: 7

Date Considered 2/17 /o(

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